## Notice of References Cited Application/Control No. 10/790,777 Examiner Christopher RoDee Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0051924	05-2002	lida et al.	430/111.4
*	В	US-5,827,632	10-1998	Inaba et al.	430/108.6
*	С	US-5,753,399	05-1998	Hayase et al.	430/111.4
*	D	US-6,664,016	12-2003	Kanbayashi et al.	430/109.3
*	E	US-5,968,701	10-1999	Onuma et al.	430/111.4
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R				·	
	s					
	Т			0.000		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
Î	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.